



Set XF 1

Contents:

H-field probe XF-R 400-1
H-field probe XF-R 3 - 1
H-field probe XF-B 3 - 1
H-field probe XF-U 2,5 - 1
E-field probe XF-E 10
Cable SMA-SMA
Case 240x185x50 mm

Instructions

NEAR FIELD PROBE SET XF 1 FREQUENCY RANGE 30 MHz up 6 GHZ

Characteristic	Description	Type
-40 -60 0 3000 MHz 6000	XF-R 400 - 1 On account of its large diameter (25 mm) this magnetic field probe is the most sensitive in our range of products. It can be used at a distance of up to 10 cm from the units. The probe detects the spatial distribution of HF magnetic fields in devices and assemblies and allows the user to draw conclusions with regard to disturbance emissions. Frequency range 30 MHz to 6 GHz Ø ca. 25 mm	registered H not registered
-40 -60 -80 0 3000 MHz 6000	XF-R 3 - 1 The near field probe is designed for the detection of HF magnetic fields with a high geometrical resolution. The field orientation and distribution can be detected by moving the probe around conductor runs, bypass capacitors, EMC components and within IC pin and supply system areas. Frequency range 30 MHz to 6 GHz; Resolution approx. 1 mm	registered H not registered
-40 -60 0 3000 MHz 6000	XF-B 3 - 1 The near field probe is designed for the detection of The near field probe is designed for the detection of magnetic fields which are emitted vertically from the surface of PCBs and is thus ideal for investigating current loops. The probe allows the measurement in confined board areas (between large controller components, for example). Frequency range 30 MHz to 6 GHz; Resolution approx. 2 mm	entering fied in the top is registered
-40 -60 -80 0 3000 MHz 6000	XF-U 2,5 - 1 The near field probe is designed for the selective detection of RF currents in conductor runs, component connections, capacitors and IC pins. The probe head has a magnetically active curb with a width of approx. 0.5 mm. The probe's curb is positioned on conductor runs, ICs or capacitor connections for a measurement. Frequency range 30 MHz to 6 GHz; Resolution approx 0,5 mm	both fields registered H Current proportional measuring
0 dB -20 -40 -60 -60 -90 3000 MHz 6000	XF-E 10 The near field probe detects electrical fields which are emitted from the surface of clocked leads. The probe head's tip is only 0.5 mm wide. Its integrated shielding prevents neighbouring leads from interfering with the measurement result. A resolution of approx. 0.2 mm is possible so that each individual conductor run can be evaluated in the layout. Frequency range 30 MHz to 6 GHz; Resolution approx 0.2 mm	Field